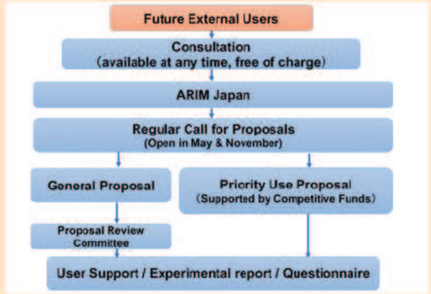
Usage flow

Only an outline is introduced below.
For details, please visit our website or contact the below-mentioned office.

1. Call for proposals

To use the equipment registered with ARIM, please submit a proposal application form. Every year, there will be periodic calls for proposals for usage around May for the second half of the relevant fiscal year (B term) and around November for the first half of the next fiscal year (A term). Kindly consult with the person in charge of the equipment beforehand before applying for the proposal. The person in charge will be introduced to you at the inquiry desk. There are also proposals based on competitive funding for priority use. Proposals that have published results will be reviewed by the JAEA-QST joint proposal review committee, and acceptance or rejection and usage time will be decided.



2. Submission of report

After implementing the proposal, please submit a usage report with the implementation content by the specified date. The usage report will be published in the next fiscal year.
The SPring-8 report for each term will also be published on the SPring-8 UI site two weeks after the 60th day following the end of each term.

3. Concerning ARIM Usage Reports

Publication of a usage report is mandatory for research support under this program. You are required to submit a usage report at the end of each fiscal year, following the completion of your usage.
The usage report is not a research paper, but rather a "Usage Report" regarding the use of ARIM's shared facilities.
The purpose is to disclose the details of experiments, measurements, analyses, and other activities conducted using ARIM facilities, as well as the results obtained; please describe any research achievements resulting from this use to the extent possible. Usage reports will be published on ARIM's Users Report, where they can be viewed, searched, and downloaded.
User's report viewing site :https://nanonet.go.jp/user_report.php
*The usage report will be published in the next fiscal year.
For details on the procedures for publishing research results generated through the use of SPring-8, please visit the JAEA-ARIM website (https://arim.jaea.go.jp/).

Usage fees and others

1.Handling fees (tax included): 13,300 yen per proposal

2.Usage fees (tax included, per 8 h-shift)

Without data provided: Basic fees: 16,660yen; priority fees: 74,990 yen
With data submitted: Basic fees: 11,660 yen; priority fees: 52,490 yen
*Prices may be revised depending on future circumstances.
For the latest information, please visit the dedicated website.
https://arim.jaea.go.jp

Access to SPring-8

Access by JR line and bus
・Approximately 40 min by bus from Aioi Station on the Sanyo Shinkansen/Sanyo Main Line
*For bus schedule, please refer to the QR code on the right.

Access by car
・Approximately 5 min from Harima-Shingu IC on the Harima Expressway

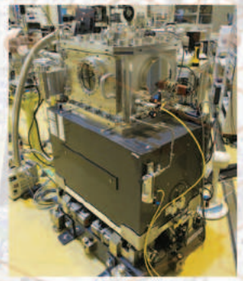
Panoramic view of SPring-8/SACLA
Courtesy of RIKEN

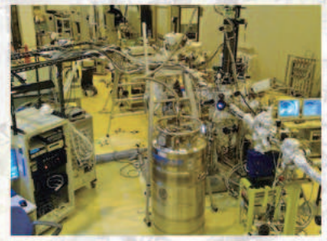
Office of JAEA for The Advanced Research Infrastructure of Materials and Nanotechnology in Japan
1-1-1 Koto, Sayo-cho, Sayo-gun, Hyogo Prefecture 679-5148
Phone: 0791-58-0822 Fax: 0791-58-2620
E-mail: harima-usersoffice@jaea.go.jp

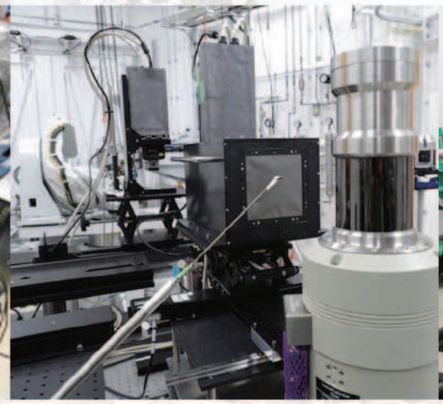
JAEA

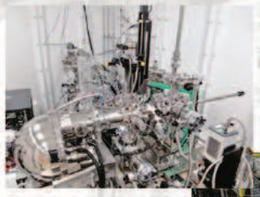
for The Advanced Research Infrastructure

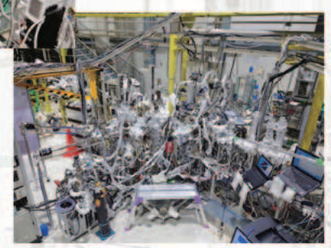
for Materials and Nanotechnology in Japan











JAEA
for The Advanced Research Infrastructure for Materials and Nanotechnology in Japan

Advanced Energy Materials Development by Synchrotron Radiation and Informatics

ARIM Japan

Implementing Agency: JAPAN ATOMIC ENERGY AGENCY

Project Overview

The Ministry of Education, Culture, Sports, Science, and Technology's Advanced Research Infrastructure for Materials and Nanotechnology in Japan (ARIM) project attempts to promote data-driven research and development throughout Japan, which has been garnering significant attention in materials development recently. The Ministry will develop an infrastructure that enables strategic use of experimental data, while developing state-of-the-art equipment and systems that allow efficient data collection.
This project comprises 26 universities and research institutes nationwide, and is divided into seven key technical areas. The Ministry will contribute to the research and development of users by forming a hub-spoke system comprising hub institutions that provide advanced facilities with strengths in each area and spoke institutions with distinctive equipment and technologies.

JAEA Beamlines

BL22XU: JAEA Actinide Science I Beamline

BL23SU: JAEA Actinide Science II Beamline

In addition to the two dedicated JAEA beamlines listed above,
we also have one provision equipment at BL14B1, which is owned by QST.

Role of Japan Atomic Energy Agency

The Japan Atomic Energy Agency (JAEA), a national research and development agency, owns two dedicated beamlines at the large synchrotron radiation facility SPring-8 and is developing a synchrotron radiation utilization technology. Together with the hub institution, University of Tokyo, and spoke institutions, Hiroshima University and Toyohashi University of Technology, it forms a technical research called "Materials that enable innovative energy conversion." To contribute to solving environmental problems such as carbon neutrality, JAEA provides and supports microstructure analysis and microfabrication technology, as well as an environment for data utilization.
Using eight analyzers installed at the JAEA' s two dedicated beamlines and the beamline owned by the National Institutes for Quantum Science and Technology, JAEA contributes to the creation of materials such as novel solar cells and power devices via measurement methods including the composition, electronic state, crystal structure, interface structure, and local structure of materials. By employing high-intensity synchrotron radiation, it can also obtain information of microsamples, uppermost surfaces, interfaces, etc.

Technical Consultation

Even if you have no experience with synchrotron radiation experiments, please feel free to contact us for the possibility of using it. Consultation is free. For details, please visit the JAEA's ARIM in-charge desk or dedicated website.

In-charge desk, JAEA Research and Development Promotion Department, Research Promotion Division
renkei.shisetsu@jaea.go.jp
<Entire JAEA facility use system>
https://tenkai.jaea.go.jp/facility/
<JAEA equipment use>
https://tenkai.jaea.go.jp/facility/3-facility/05-support/index-14.html
<JAEA ARIM>
https://arim.jaea.go.jp

Obtained Data and Results

As a general rule, for the proposals supported by this project, the obtained experimental data will be provided and the results will be published. If you would like to keep your results undisclosed, the JAEA's independent project can support you with that. For details, please contact the in-charge desk.

EXPERIMENTAL DEVICE

BL22XU: JAEA Actinide Science I Beamline

Hard X-ray photoelectron spectrometer

- Enables acquisition of bulk information by reducing the effect of surface contamination
- Effective for the electronic structure analysis of samples for which surface cleaning treatment is difficult and devices with internal nanoscale multilayer structures
- The excitation light energy (6, 8, and 10 keV) can be selected. In addition, it is possible to select the detection depth according to a specific purpose.

[Example of application] Damage analysis of radiation-resistant spin-driven thermoelectric devices

XAFS measuring system

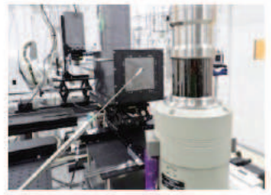
- Enables XAFS using high-luminance and high-energy X-rays from an undulator
- Handles time-resolved quick measurement (Quick-XAFS)
- Various detectors such as ion chambers, NaI scintillation, and Ge semiconductors are available
- Preparation of a cryostat for low-temperature measurement

[Examples of application] Structural and electronic-state analyses for functional molecular design, structural and electronic-state analyses for Rh (III) inducer development, etc.

The apparatus for imaging and measuring material stress

- Enables internal strain and stress distribution in metallic materials and imaging
- Enables actual environment in situ measurement using a high-temperature (maximum 900 ℃) and load (maximum 5 kN) device
- Enables time-resolved measurement at a maximum speed of 200 Hz for strain and stress and 2000 Hz for imaging by utilizing multiple two-dimensional detectors simultaneously

[Examples of application] Evaluation of stress, strain, and dislocation density during deformation in metallic materials, observation of a melting solidification phenomenon during laser processing, etc.



κ-type X-ray diffractometer

- κ-type diffractometer suitable for surface structure analysis
- In addition to the standard six axes, it has a rotation axis in the horizontal plane for the entire system
- Enables simultaneous measurement of electrochemical properties using a potentiostat
- The sample temperature is up to 10 K, obtained using a He circulation-type refrigerator and up to 1000 K by utilizing an electric furnace

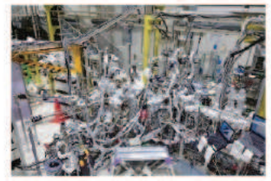
[Examples of application] Synthesis and microstructure analysis of barium titanate nanocubes

BL23SU: JAEA Actinide Science II Beamline

Surface chemistry experiment apparatus

- Enables in situ observation and real-time analysis of the dynamics of chemical reactions such as adsorption/desorption and oxidation/reduction on metal and semiconductor surfaces
- Enables surface cleaning in the surface preparation chamber via Ar ion sputtering and heating up to 1450 K
- LEED and AES equipment included for reconstructed surface and chemical composition observations
- Enables supply of gas molecules with different kinetic energies to the sample surface using a gas dozer and supersonic molecular beam apparatus.

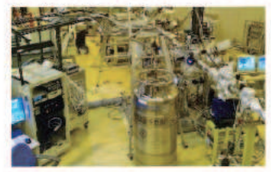
[Examples of application] Elucidation of the graphene formation process, study on an insulating film formation process on a SiC surface, surface interface analysis for GaN-based power electronics development, observation of a chemical bonding state of a hafnium silicide oxidation process, etc.



Soft X-ray photoelectron spectrometer

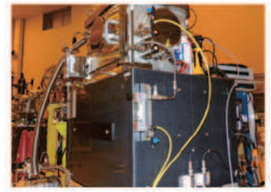
- Photoelectron spectrometer that can also determine band structure via angle-resolved photoemission spectroscopy (ARPES)
- Enables detailed electronic structure analysis of rare earth and 3d transition metal compounds

[Examples of application] Molecular structure of uranium compounds, molecular structure of rare earth compounds



Scanning transmission X-ray microscope (STXM)

- Element-selective chemical analysis tool with nanoscale spatial resolution
- Enables two-dimensional mapping of the transmitted light (absorption) intensity by irradiating the sample with soft X-rays focused to several tens of nanometers and scanning the sample
- A powerful method for analysis of fine particle samples and samples with significant heterogeneity
- Enables an analysis of elemental distribution, and valence and chemical bonding states for a wide range of elements such as lanthanides, actinides, 3d transition metal elements, and nitrogen and oxygen in organic compounds
- Light energy: 400–1900 eV; best spatial resolution: 30 nm (when a 25-nm FZP is used); sample temperature: 300 K

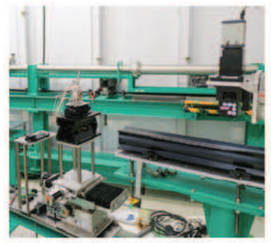


BL14B1: QST Extreme Quantum Dynamics II Beamline

Energy-dispersive XAFS measuring system

- Conventional X-ray absorption spectroscopy (XAFS) using a double crystal spectrometer
- Employs a 36-element semiconductor detector in the fluorescence method
- The sample temperature is between 20 and 1073 K.
- The atmosphere containing carbon monoxide and nitrogen monoxide can be controlled using a gas control system, and a gas component analysis can also be performed using a quadrupole mass spectrometer.
*Also enables time-resolved XAFS using a curved analyzing crystal

[Examples of application] In situ XAFS analysis of hydrazine hydrate oxidation catalyst, elucidation of the reaction mechanism of secondary batteries using polyoxometalate compounds as electrode materials, etc.



*There may be additions in the future. Please check the website (https://arim.jaea.go.jp) for the latest registered device.